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January 5, 2006

Fo: Commissioner for Patents P.O. Box 1450 Alexandria, VA 22313-1450

Fr: George O. Saile, Reg. No. 19,572 28 Davis Avenue Poughkeepsie, NY 12603

Subject: Serial No. 10/748,736 12/30/05

Wong Ee Hua et al.

WAFER LEVEL SUPER STRETCH SOLDER

SUPPLEMENTAL INFORMATION DISCLOSURE STATEMENT

Enclosed is Form PTO-1449, Information Disclosure Citation In An Application.

The following Patents and/or Publications are submitted to comply with the duty of disclosure under CFR 1.97-1.99 and 37 CFR 1.56.

CERTIFICATE OF MAILING

I hereby certify that this correspondence is being deposited with the United States Postal Service as first class mail in an envelope addressed to: Commissioner for Patents, P.O. Box 1450, Alexandria, VA 22313-1450, on January 6, 2006.

Stephen B. Ackerman, Reg. # 37761

Signature/Date_

U.S. Patent 4,545,610 to Lakritz et al., "Method for Forming Elongated Solder Connections Between a Semiconductor Device and a Supporting Substrate," discloses a process for forming elongated solder terminals to connect a plurality of pads on a semiconductor device to a corresponding plurality of pads on a supporting substrate.

U.S. Patent 6,432,744 to Amador et al., "Wafer-Scale Assembly of Chip-Size Package," discloses a wafer-scale assembly apparatus for integrated circuits and method for forming the wafer-scale assembly.

Sincerely,

Stephen B. Ackerman, Reg. No. 37761 Form PTO-1449 Doctor (Humber (Openna) IME-03-005 - NEORMATION DISCLOSURE CITATION IN AN APPLICATION (Use several shouls if necessary) U. S. PATENT DOCUMENTS DOCUMENT NUMBER DATE HAME AUNG DATE CUH NBCU4 589 438 108 FOREIGN PATENT DOCUMENTS Translation OOCUMENT NUMBER CLASS OUTE COUNTRY SUBCLASS YES OTHER DOCUMENTS (Including Author, 1760, Dalo, Portinora Pagos, Elc.)

EXAMINER: Initial if citation considered, whether or not citation is in conformance with MPEP § 609; Draw line through citation if not in conformance and not considered. Include copy of this form with next communication to the applicant.

DATE CONMIDERED

EXAMMER